5/9/2009

RELIABILITY MONITOR REPORT
FOR

MFN 1.2µm High Voltage BiCMOS

MAXIM Integrated Products

120 San Gabriel Dr.
Sunnyvale, CA 94086

This Report was prepared by
Maxim Reliability Engineering

Summary:

The data in the tables that follow was generated as the result of an on-going Process Reliability Monitor. The specific products in this process monitor are:

806-0683-20

The calculated failure rate for devices using this process is:

FAILURE RATE: **MTTF (YRS): 14921** **FITS: 7.7**

The parameters used to calculate this failure rate are as follows:

Cf: 60% **Ea: 0.7** **Tu: 25 °C**

The reliability data follows and in this section is the detailed reliability data by stress. The reliability data section includes the latest data available. This report covers data between and .

Process Information:

Process Description: MFN 1.2µm High Voltage BiCMOS

OPERATING LIFE

DESCRIPTION	DATE CODE	TEST VEHICLE	CONDITION	READPOINT	QUANTITY	FAILS	LOT NO.
HIGH TEMP OP LIFE	0732	806-0683-20	135C	1000 HRS	77	0	NZ1AD4017Q
				Total:		**0**	

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